



• General Description

This silicon carbide Power MOSFET device has been developed using ZMJ's advanced 2nd generation SiC MOSFET technology. The device features a very low RDS(on) over the entire temperature range combined with low capacitances and very high switching operations. It improves application performance in frequency, energy efficiency, system size and weight reduction.

• Features

- High Blocking Voltage
- High Speed Switching With Low Capacitances
- Low $R_{DS(ON)}$ to Minimize Conductive Loss
- Low Gate Charge For Fast Switching
- Low Thermal Resistance
- 100% Avalanche Tested
- AEC-Q101 Qualified

• Application

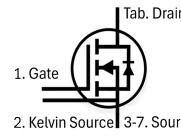
- Motor Drives
- On Board Charger
- DC-DC
- Auxiliary Drives

• Ordering Information:

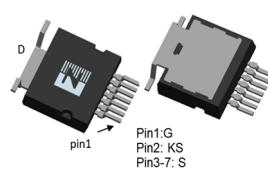
Part NO.	ZMCA040R120T2
Marking	ZMC040R120
Packing Information	REEL TAPE
Basic ordering unit (pcs)	700

• Absolute Maximum Ratings ($T_A=25^\circ\text{C}$,unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Max.	Unit
Drain-Source Voltage	V_{DS}		-	1200	V
Gate-Source Voltage ^①	V_{GS}	Transient Voltage	-10	25	V
	V_{GS}	Static Voltage	-10	24	V
Recommended turn on gate voltage	$V_{GS(on)}$		15	18	V
Recommended turn off gate voltage	$V_{GS(off)}$		-4	0	V
Continuous Drain Current	I_D	$V_{GS}=18\text{V}, T_C=25^\circ\text{C}$	-	53	A
	I_D	$V_{GS}=18\text{V}, T_C=75^\circ\text{C}$	-	43	A
	I_D	$V_{GS}=18\text{V}, T_C=100^\circ\text{C}$	-	38	A
Pulsed Drain Current ^①	I_{DM}	Pulsed; $t_p \leq 10 \mu\text{s}; T_C = 25^\circ\text{C}$	-	212	A
Total Power Dissipation	P_D	$T_C=25^\circ\text{C}$	-	211	W
Total Power Dissipation	P_D	$T_A=25^\circ\text{C}$	-	3.0	W
Operating Junction Temperature	T_J		-55	175	°C
Storage Temperature	T_{STG}		-55	175	°C
Single Pulse Avalanche Energy	E_{AS}	$L=0.5\text{mH}, V_{GS}=18\text{V}, R_g=25\Omega,$	-	529	mJ
ESD Level (HBM)			CLASS 2		



$V_{DS} = 1200\text{V}$
 $R_{DS(ON)} = 36\text{m}\Omega$
 $I_D = 53\text{A}$





•Thermal resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R_{thJC}	-	-	0.71	°C/W
Thermal resistance, junction-ambient	$R_{thJA}^{(2)}$	-	-	50	°C/W
Soldering temperature	Tsold	-	-	260	°C

•Electronic Characteristics (Tj=25°C,unless otherwise specified)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	1200	-	-	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS}=V_{DS}, I_D=5mA$	2	2.7	4	V
Drain-Source Leakage Current	I_{DSS}	$V_{GS}=0V, V_{DS}=1200V$	-	-	10	μA
Gate- Source Leakage Current	I_{GSS}	$V_{GS}=-10V, V_{DS}=0V$	-	-	-100	nA
	I_{GSS}	$V_{GS}=25V, V_{DS}=0V$	-	-	100	nA
Static Drain-source On Resistance	$R_{DS(ON)}$	$V_{GS}=18V, I_D=30A, Tj=25^\circ C$	-	36	43	$m\Omega$
		$V_{GS}=18V, I_D=30A, Tj=175^\circ C$	-	73	-	$m\Omega$
		$V_{GS}=15V, I_D=30A, Tj=25^\circ C$	-	43	-	$m\Omega$
Forward Transconductance	g_{FS}	$V_{DS}=10V, I_{SD}=30A$	-	14	-	S
Diode Forward Voltage	V_{FSD}	$V_{GS}=-4V, I_{SD}=30A$	-	4.4	5	V

•Dynamic characteristics (Tj=25°C,unless otherwise specified)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input capacitance	C_{iss}	$f = 100KHz, V_{DS}=800V, V_{GS}=0V$	-	2192	-	pF
Output capacitance	C_{oss}		-	90	-	
Reverse transfer capacitance	C_{rss}		-	2	-	
Output Charge	Q_{oss}	$f = 100KHz, V_{GS}=0V, V_{DS}=0V \text{ to } 800V$	-	121	-	nC
Coss Stored Energy	E_{oss}		-	33	-	μJ
Gate Resistance	R_g	$f = 1MHz$	-	1.5	-	Ω
Total gate charge	Q_g	$V_{DD} = 800V, I_D = 30A, V_{GS} = -4V/18V$	-	85.9	-	nC
Gate - Source charge	Q_{gs}		-	24.9	-	
Gate - Drain charge	Q_{gd}		-	30.0	-	
Turn-ON Delay time	$t_{D(on)}$	$V_{GS}=-4V/18V, V_{DS}=800V, R_G = 10\Omega, I_D = 30A$	-	18	-	ns
Turn-ON Rise time	t_r		-	36	-	ns
Turn-Off Delay time	$t_{D(off)}$		-	48	-	ns
Turn-Off Fall time	t_f		-	71	-	ns
Turn-On Energy	E_{on}		-	1068	-	μJ
Turn-Off Energy	E_{off}		-	1080	-	μJ
Reverse Recovery Time	t_{rr}	$V_{DD}=100V, dI_S/dt = 260A/us, I_S=30A$	-	24	-	ns
Reverse Recovery Charge	Q_{rr}		-	50	-	nC

Fig.1 Gate-source voltage as a function of gate charge;Typical values;T_j=25°C

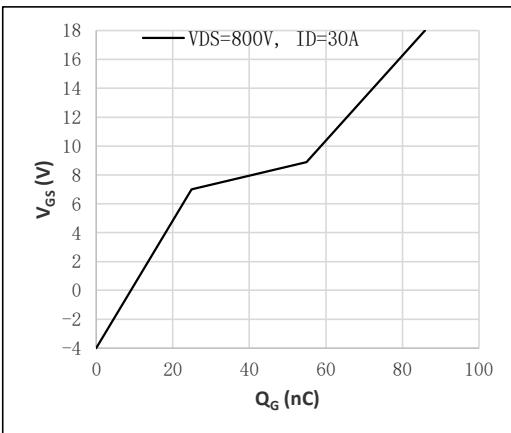


Fig.3 Output characteristics: drain current as a function of drain-source voltage;Typical values;T_j=25°C

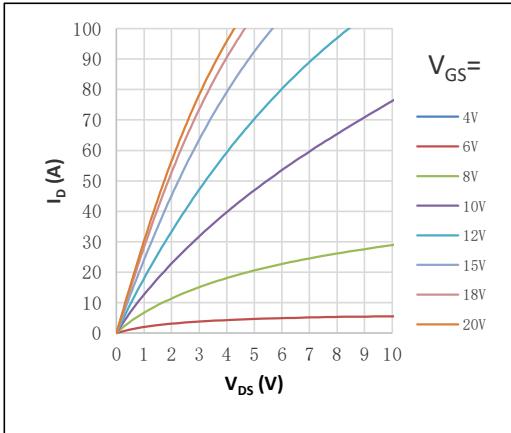


Fig.5 Gate-source threshold voltage as a function of junction temperature;Typical values

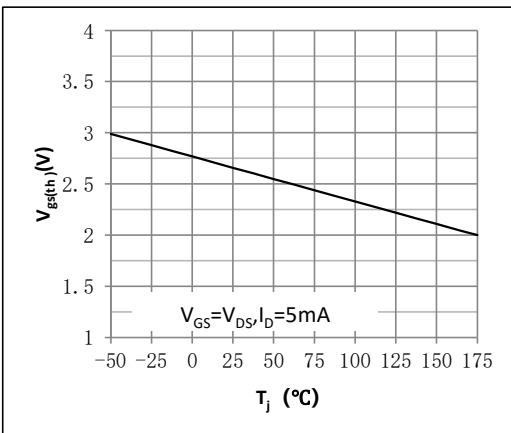


Fig.2 Input, output and reverse transfer capacitances as a function of drain-source voltage;Typical values;T_j=25°C

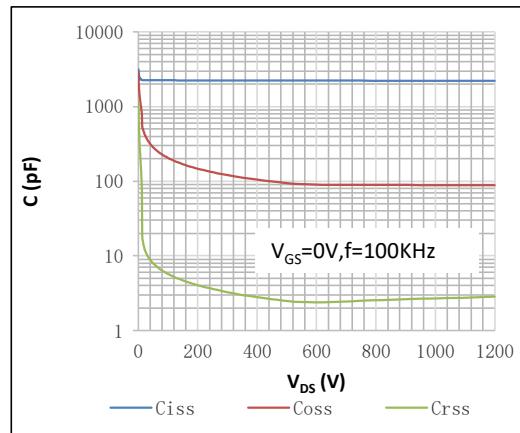


Fig.4 Output characteristics: drain current as a function of drain-source voltage;Typical values;Expanded curve;T_j=25°C

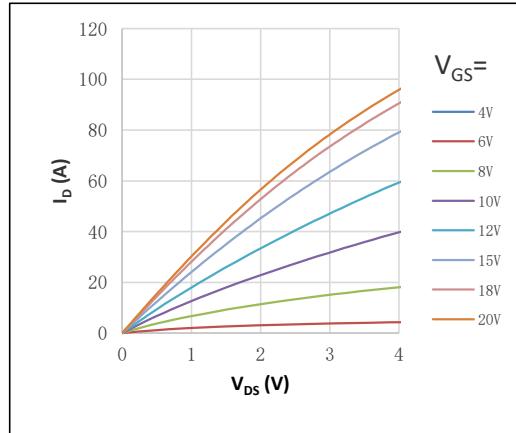


Fig.6 Drain-source on-state resistance as a function of drain current;Typical values;T_j=25°C

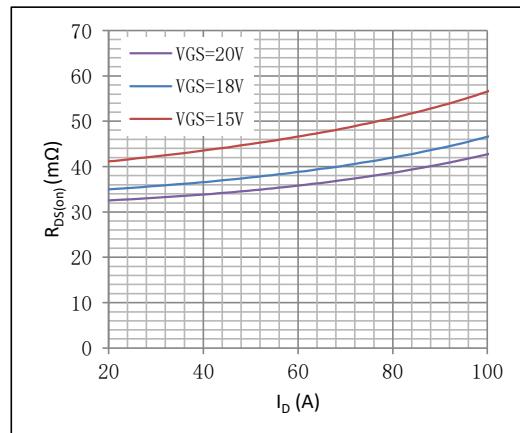


Fig.7 Drain-source on-state resistance as a function of gate-source voltage;Typical values

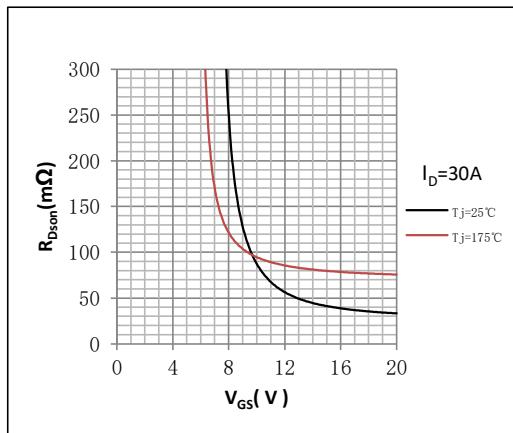


Figure 9. Source (diode forward) current as a function of source-drain (diode forward) voltage;Typical values

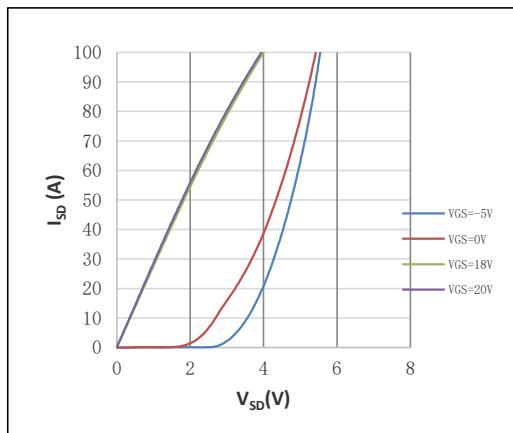


Fig.11 Safe operating area: continuous and peak drain currents as a function of drain-source voltage;Calculative values

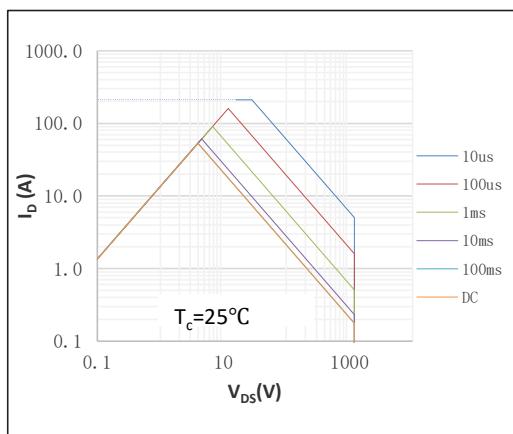


Fig.8 Normalized drain-source on-state resistance factor as a function of junction temperature;Typical values
Normalized On-Resistance=RDSon/RDSon(25°C)

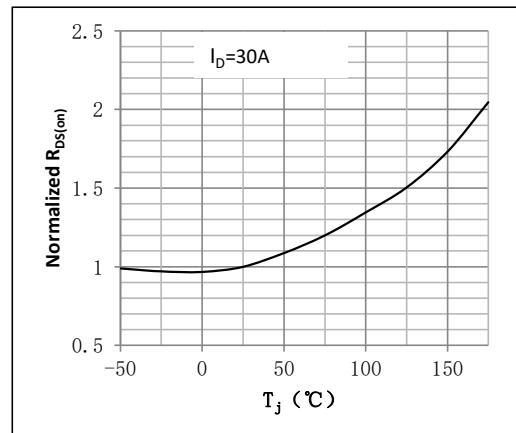


Figure 10. Transfer characteristics: drain current as a function of gate-source voltage;Typical values

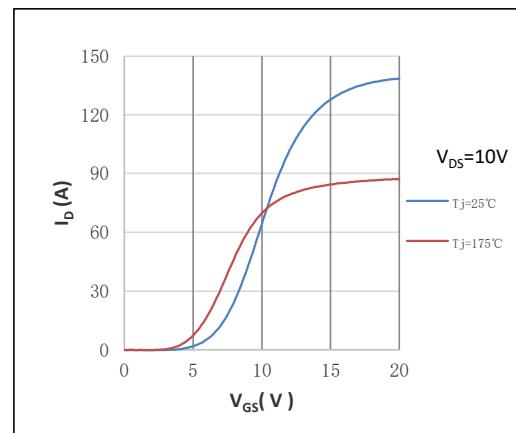


Fig.12 Continuous drain current as a function of case temperature^①;Calculative values

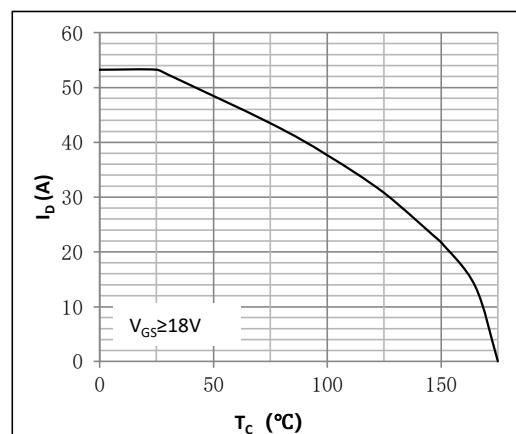


Fig.13 Drain-source breakdown voltage as a function of junction temperature;Typical values
Normalized BVDSS=BVDSS/BVDSS(25°C)

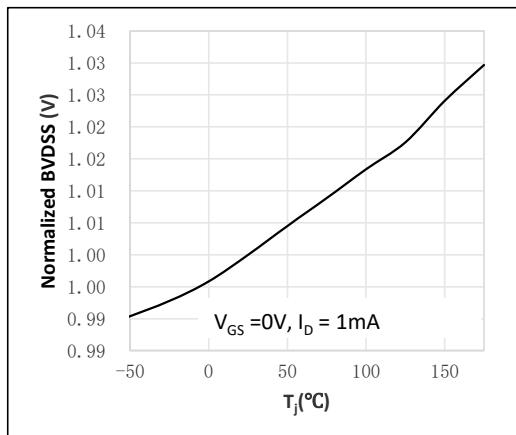


Fig.14 Normalized total power dissipation as a function of case temperature;Calculative values
Normalized Power Dissipation=Pd/Pd(25°C)

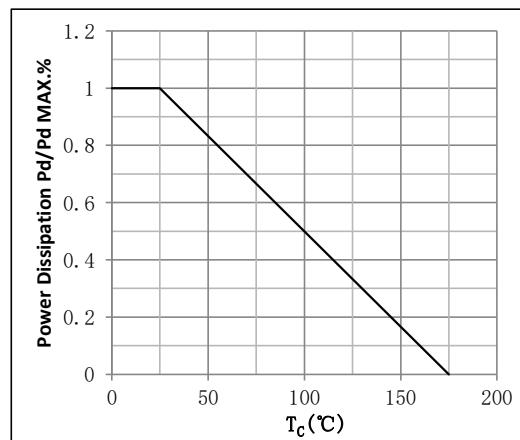


Fig.15 Transient thermal impedance from junction to case as a function of pulse duration; max values

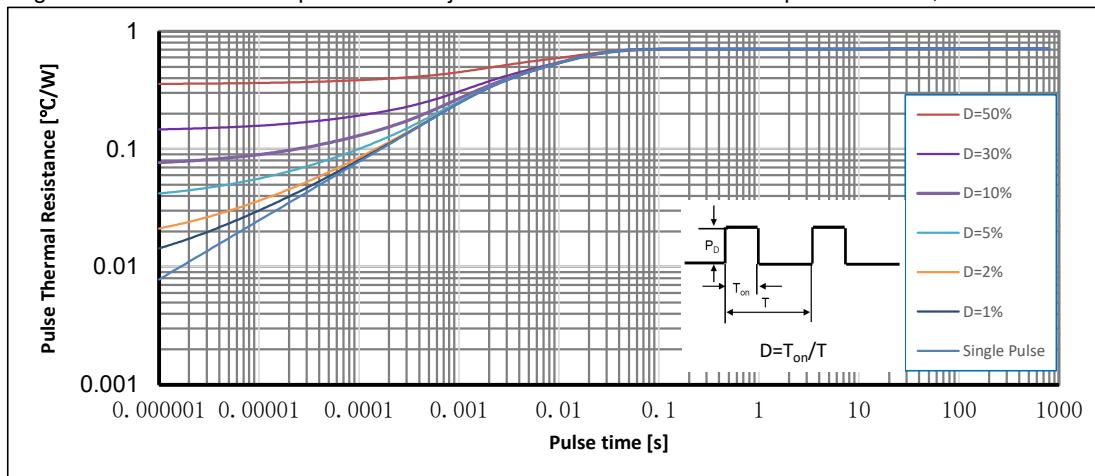
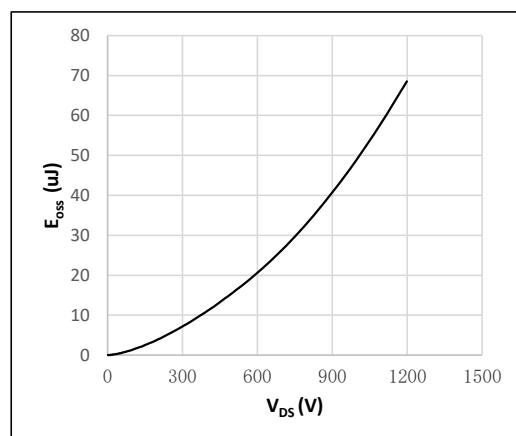
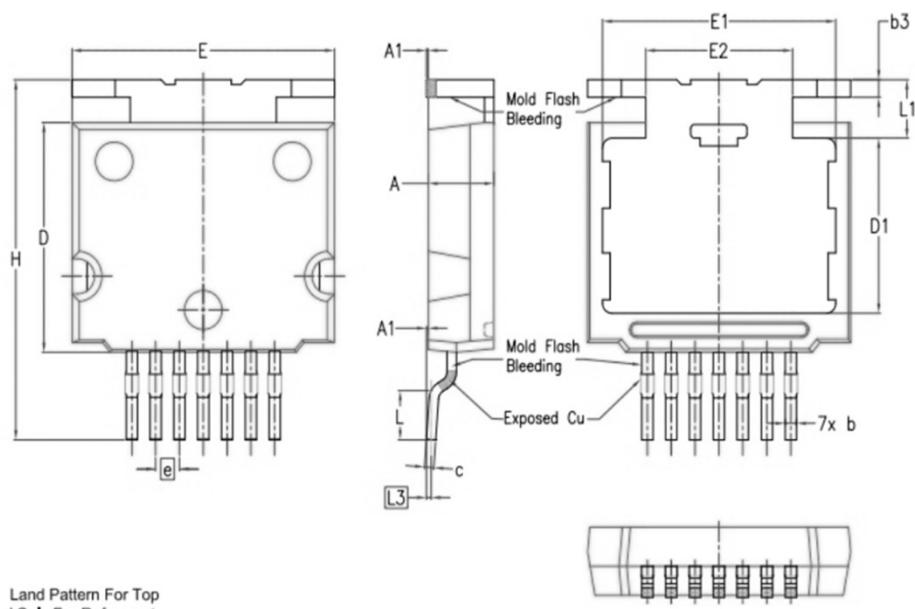


Fig.16 Output capacitor stored energy as a function of drain-source voltage;Typical values;
Tj=25°C





•T2PAK Package Outline



SYMBOL	DIMENSIONS		
	MIN.	NOM.	MAX.
A	3,40	3,50	3,60
A1	0,00	0,10	0,25
b	0,50	0,60	0,70
b3	0,80	0,90	1,00
c	0,40	0,50	0,60
c2	0,40	0,50	0,60
D	11,70	11,80	11,90
D1	8,80	9,00	9,10
E	13,90	14,00	14,10
E1	12,30	12,40	12,50
E2	7,75	7,80	7,85
e	1,27 BSC		
H	18,00	18,50	19,00
L	2,30	2,50	2,75
L1	—	3,05	—
L3	—	0,26	—
L5	1,70	1,90	2,15

Note:

- ① The value of R_{θJA} is measured with the device in a still environment with TA=25°C
- ② Practically the current will be limited by PCB, thermal design and operating temperature. VGS=18V.

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Version	Date	Change
A	2025/4/16	New